

ABSTRACT OF THE DISCLOSURE

2 According to one embodiment, verifying a reticle may include patterning an inspected
3 layer (102-2) according to a reticle pattern, depositing a contrast enhancing layer (104-0) on
4 a patterned layer (102-2), and inspecting a reticle patterned formed in the inspected layer
5 (102-2).

FOIA "b(7)(E)" 4/26/2000